

SEP 20 2004

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Sheet 1 of 2

FORM PTO-1449 (REV. 7-80)	U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE	ATTY. DOCKET NO. NIP-261	SERIAL NO.
LIST OF DOCUMENTS CITED BY APPLICANT (Use several sheets if necessary)		APPLICANT Y. TAKEZAWA et al	
		FILING DATE February 26, 2002	GROUP

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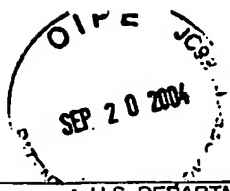
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						YES	NO
DM	AL 11-330185	11/30/99	Japan (w/ English Abstract)			<input type="checkbox"/>	<input type="checkbox"/>
	AM 2000-131243	05/12/00	Japan (w/ English Abstract)			<input type="checkbox"/>	<input type="checkbox"/>
	AN 11-235097	08/27/99	Japan (w/ English Abstract)			<input type="checkbox"/>	<input type="checkbox"/>
	AO 9-222393	08/26/97	Japan (w/ English Abstract)			<input type="checkbox"/>	<input type="checkbox"/>
	AP 10-115601	05/06/98	Japan (w/ English Abstract)			<input type="checkbox"/>	<input type="checkbox"/>

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, etc.)

DM	AR	T. Ikeda et al, "Development of the Ultrasonic Degradation Tester for Low Voltage Cables", TRANSACTIONS OF THE INSTITUTE OF ELECTRICAL ENGINEERS OF JAPAN, Vol. 120-B, No. 11, pp. 1437-1442, 2000.
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	DOCUMENT	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
						YES	NO
DM	AL 11-118773	04/30/99	Japan (w/ English Abstract)			<input type="checkbox"/>	<input type="checkbox"/>
I	AM 10-19856	01/23/98	Japan (w/ English Abstract)			<input type="checkbox"/>	<input type="checkbox"/>
	AN 7-35732	02/07/95	Japan (w/ English Abstract)			<input type="checkbox"/>	<input type="checkbox"/>
	AO 7-245869	09/19/95	Japan (w/ English Abstract)			<input type="checkbox"/>	<input type="checkbox"/>
	AP					<input type="checkbox"/>	<input type="checkbox"/>

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